

Form PTO-1469		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M72-1684		SERIAL NO. 09 072349	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.			
				FILING DATE April 4, 2001		GROUP 2829	
U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
✓	70R1309022	4/4/2001	Micron Technology, Inc.				
	AS						
	AC						
	AD						
OTHER REFERENCES (including Author, Title, Date, Published Pages, Etc.)							
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
EXAMINER <i>anh Nguyen</i>				DATE CONSIDERED 10/18/2000			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with final communication to applicant.							

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1684		SERIAL NO. 09/037,248	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.		FILING DATE April 4, 2001	
				GROUP 2858, 2859			
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
VN	AA 6,004,471	12/21/1999	Chuang				
VN	AB 5,550,526	8/27/1996	Notzhead				
	AC						
	AD						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
EXAMINER <i>anh Nguyen</i>				DATE CONSIDERED 10/18/2002			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

EVO 77333999

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.  
MO22-1684

SERIAL NO. 09/827248

LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)

**JUL 29 2007**

**APPLICANT**  
**David R. Henderson**

**FILING DATE**  
**April 4, 2001**

GROUP 2829

TRADEMARKED DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
	AA 3,440,409	4/22/99	Goldman et al.			
	AB 3,614,355	10/19/97	Quinn			
	AC 3,683,305	8/8/93	Bathman et al.			
	AD 4,333,081	6/1/83	Francis			
	AE 4,518,964	5/21/85	Faris			
	AF 5,703,555	11/9/97	Hahn			
	AG 5,144,334	8/25/97	Curtis			
	AH 5,342,868	9/29/94	Six et al.			
	AI 5,406,108	4/11/85	Whitney			
	AJ 5,434,646	7/25/83	McGowan et al.			
	AK 5,445,417	8/28/95	Hartman et al.			

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
VN	AL	2336778	2/1977	France				
VN	AM	56-12521	2/1981	Kobayashi, Japan				
VN	AN	2-258462	11/1990	Yamashiki, Japan				
	AO							
	AP							

**OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)**

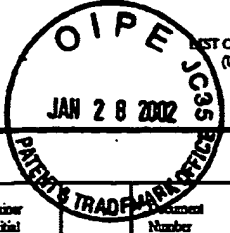
VN	AR	Application Order Temperature Sensors, Wetlow Electrical Manufacturing Company Catalog, pp. 775-778, 1992/1993. (most unavailable)
VN	AS	3-Die Array System of Resistor and Thermoelectric Properties of Epitaxial Films or Mixed Materials in Thin Films Evaporated Under Ultra High Vacuum, Lockwood, Lefebvre, Richman, Serrus, & Gombault, J. Phys. (D) France, Vol. 3, pp. 609-618, 96-97 (Abstract only)
VN	AT	Temperature Monitoring for CO Control in SOV Catalytic-converter, Jeffrey Portier and Wayne Rabinow, pp. 111-112, 114, 116, 691/1997.

**EXAMINER**

DATE CONSIDERED

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 608; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE <div style="border: 1px solid black; border-radius: 50%; width: 100px; height: 100px; display: flex; align-items: center; justify-content: center; margin: 0 auto;"> <div style="writing-mode: vertical-rl; transform: rotate(180deg);">U.S. PATENT &amp; TRADEMARK OFFICE</div> <div style="text-align: center;">           JUL 29 2002         </div> </div>		ATTY. DOCKET NO. M122-16804		PRIORITY SERIAL NO. 09137829 011827248		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT David R. Hembree			PRIORITY GROUP 2858 2829			
		PRIORITY FILING DATE August 21, 1998						
U.S. PATENT DOCUMENTS								
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
	AE 4,500,216	12/24/83	Egawa					
	AB 4,794,355	3/15/88	Sullivan					
	AC 5,475,312	10/12/95	Smith					
	AD 7,495,662	2/5/96	Farnworth et al.					
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
AE		391-09/032-184; Filed 3/22/83; Akman et al.; Amendment filed 12/18/80; CPA filed 7/28/80; Amendment filed 3/2/80; Amendment filed 8/22/80;						
AF		Advertisement for Probe Technology; www.idinet.com; Interconnect Device, Inc.; 1 page; 3/6/98						
AG		Good Things Come in Small Packages; www.johnstech.com/~jstn/works/pack6.html; 1 page; 2/5/98						
AH		Product Description for Double Ended Probes, B1052 Series; www.testprobe.com/products/b1052.html; Rika Denchi America, Inc.; 1 page; 2/4/98						
AI		Product Description for Test Centers, RM-600 Series Probes; www.testprobe.com/products/rm600.html; Rika Denchi America, Inc.; 1 page; 2/4/98						
AJ		Product Description for Cost Effective Interconnections for High I/O Products; www.testprobe.com/products/56.html#b1303; Rika Denchi America, Inc.; 1 page; 2/4/98						
AK		Product Description for Ball Grid Probe B1302-C2; www.testprobe.com/products/56.html#b1302; Rika Denchi America, Inc.; 1 page; 2/4/98						
AL		Product Description for Ten Socket Contacts; www.johnstech.com/~jstn/works/pack6.html; 1 page; 2/5/98						
EXAMINER <i>rmh Nguyen</i>		DATE CONSIDERED 03/10/03						
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicants.								

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1684	SERIAL NO. 09/227,248		
BEST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT David R. Hembree			
				FILING DATE April 4, 2001			
				GROUP 2829			
U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
VN	AA 3,440,407	4/22/69	Oebates et al.				
	AB 3,614,345	10/19/71	Quinn				
	AC 3,683,306	8/8/72	Bethins et al.				
	AD 4,332,081	6/1/82	Francis				
	AE 4,518,944	5/21/83	Faris				
	AF 4,703,553	11/3/87	Habner				
	AG 5,141,334	8/25/92	Castles				
	AH 5,347,869	9/20/94	Shie et al.				
	AI 5,406,109	4/11/95	Whitney				
	AJ 5,450,646	7/25/95	McArthur et al.				
	AK 5,446,437	8/29/95	Banien et al.				
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
	AB 333,678	3/0/72	France			Yes	No
	AM 56,428,51	3/0/83	Kobayashi, Japan				
	AN 3,368,463	11/0/90	Yamashita, Japan				
	AO						
	AP						
OTHER REFERENCES (excluding Author, Title, Date, Persistent Pages, Etc.)							
	AR	Apparatus and Temperature Sensor, Wireless Electrical Manufacturing Company Catalog, pp. 773, 778, 1382/2, 882.					
	AS	In One-way System of Resonance and Thermodynamic Properties of Carbonaceous Mixed Materials in Two-Dimensional Layers Under High Pressure, Lockwood, L. H., et al., J. Chem. Phys., pp. 408-413, 64-65 (1976).					
	AT	Temperature Monitoring for CO Control in D/G Locomotives, Rolling Stock and Marine Engines, pp. 111-113, 114, 116, 280/3, 783.					
EXAMINER <i>rukh Nguyen</i>				DATE CONSIDERED 10/18/2002			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. M12-1684		SERIAL NO. 09/21,248	
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					GROUP 2829			
U.S. PATENT DOCUMENTS								
Examiner Initial	Doc. Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
<div style="font-size: 2em;">↓</div>	AA	5,612,574	3/18/97	Summerfelt et al.			<div style="font-size: 2em;">/</div>	
	AB	5,719,333	2/17/98	Hosoi et al.				
	AC	5,831,333	11/3/98	Malladi et al.				
	AD	5,919,348	7/6/99	Barrow et al.				
	AE	5,551,283	9/3/96	Manaka et al.				
	AF	5,492,011	2/20/96	Amano et al.				
	AG							
	AH							
	AJ							
FOREIGN PATENT DOCUMENTS								
	Document Number	Date	Country	Class	Subclass	Translation		
	AK					Yes	No	
	AL							
	AM							
	AN							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AP	"DTC and RDC Thermostat"; <a href="http://www.dumondfine.com/temts.html">http://www.dumondfine.com/temts.html</a> ; 1/1/00; 3 pages.						
	AR	"DS-5031-1 Linearized 4 Wire RTD Input"; <a href="http://www.dalog.com/650315.html">http://www.dalog.com/650315.html</a> ; 1/1/00; 3 pages.						
	AS	"RTD"; <a href="http://www.minicon.com/rtde.html">http://www.minicon.com/rtde.html</a> ; 1/1/00; 3 pages.						
	AT	"Low Cost Thermal Resistor (TM) over thin film RTD"; <a href="http://www.minico.com/t1363aa.html">http://www.minico.com/t1363aa.html</a> ; 1/1/00; 1 page.						
	AU	"Silicon Processing for the M151 Em7, Volume 1 - Process Technology, Second Edition; C. Wolf et al.; 2000; pp. 23-25 and pp. 841-841.						
EXAMINER <i>ruul Nguy</i>				DATE CONSIDERED 10/16/2002				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-16804	PRIORITY SERIAL NO. 097137.629-09/827248	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT David R. Hembree		
				PRIORITY FILING DATE August 21, 1998	PRIORITY GROUP 3858-2829	
U.S. PATENT DOCUMENTS						
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA	4,560,216	12/24/85	Egawa		/
	AB	4,754,555	7/5/88	Stillman		
	AC	5,475,317	12/12/95	Smith		
	AD	5,495,667	3/5/96	Faraworth et al.		
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)						
	AE	<del>SOL 09/033,184, Filed 3/27/98, Abram et al., Amendment filed 12/18/00, CPA filed 9/28/00, Amendment filed 3/3/00, Amendment filed 8/23/00.</del> <del>Original Application filed 3/27/98, Pending Claims.</del>				
VN	AF	Advertisement for Probe Technology; <a href="http://www.idinet.com">www.idinet.com</a> ; Interconnect Devices, Inc., 1 page; 3/6/98				
VN	AG	Good Things Come In Small BGA/CSP Packages; <a href="http://www.johnstech.com/4/handbook/page9.html">www.johnstech.com/4/handbook/page9.html</a> ; 1 page; 3/5/98				
VN	AH	Product Description for Double Ended Probes, B1052 Series; <a href="http://www.testprobe.com/products/b1052.html">www.testprobe.com/products/b1052.html</a> ; Rita Denshi America, Inc.; 1 page; 2/4/98.				
VN	AI	Product Description for Test Centers, RM-500 Series Probes, <a href="http://www.testprobe.com/products/rm500.html">www.testprobe.com/products/rm500.html</a> ; Rita Denshi America, Inc.; 1 page; 2/4/98.				
VN	AJ	Product Description for Cost Effective Interconnections for High I/O Products; <a href="http://www.testprobe.com/products/so.htm#b1303">www.testprobe.com/products/so.htm#b1303</a> ; Rita Denshi America, Inc.; 1 page; 2/4/98.				
VN	AK	Product Description for Ball Grid Probe B1303-C3; <a href="http://www.testprobe.com/products/so.htm#b1303">www.testprobe.com/products/so.htm#b1303</a> ; Rita Denshi America, Inc.; 1 page; 2/4/98.				
VN	AL	Product Description for Test Socket Connects; <a href="http://www.johnstech.com/4/handbook/page9.html">www.johnstech.com/4/handbook/page9.html</a> ; 1 page; 3/5/98				
EXAMINER <i>mk Nguyen</i>				DATE CONSIDERED 03/22/2002		
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.						

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Form PTO-1449

**JUL 06 2001**

**U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE**

**ATTY. DOCKET NO.**  
M122-1684

**SERIAL NO.**  
09/827,248

**LIST OF ART CITED BY APPLICANT**  
(Use several sheets if necessary)

**APPLICANT**  
Micron Technology, Inc.

**FILING DATE**  
April 4, 2001

**GROUP**  
2829

**U.S. PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA 5,378,311	1/3/95	Nagayama et al.			
	AB					
	AC					
	AD					

**OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)**

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**EXAMINER** *ruh Nguy*

**DATE CONSIDERED** *03/22/2002*

\*EXAMINER: Initialed if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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Form PTO-1449

**JUN 19 2003**

LIST OF ARTS CITED BY APPLICANT  
(Use several sheets if necessary)

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.  
M122-1684

SERIAL NO.  
09/827,248

APPLICANT  
Micron Technology, Inc.

FILING DATE  
April 4, 2001

GROUP  
2855 2829

U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
VN	AA	5,670,066	9/23/1997	Barnes et al.			
	AB	6,377,060 B1	4/23/2002	Burkhardt et al.			
	AC	4,912,600	3/1990	Jaeger et al.	361	700	
	AD	5,325,052	6/28/1994	Yamashita			
	AE	4,355,463	10/26/1982	Burns			
	AF	3,710,251	1/9/1973	Hagge et al.			
	AG	5,436,494	7/1995	Moskhi	257	467	
	AH	5,969,639	10/1999	Lauf et al.	340	870.17	

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
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EXAMINER *mark Nguyen*

DATE CONSIDERED *08/06/03*

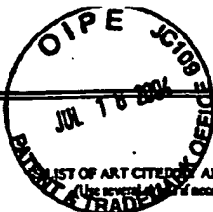
\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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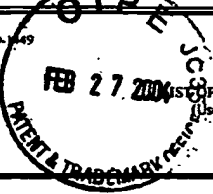
Form PTO-1419		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M22-16804		047827248 PRIORITY SERIAL NO. 00133,629	
DEC 15 2003 U.S. PATENT & TRADEMARK OFFICE OFFICE OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT David R. Hembree		PRIORITY FILING DATE August 21, 1998	
				PRIORITY GROUP 2829		PRIORITY GROUP 2829	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA	4,560,216	12/24/85	Egawa			
	AB	4,754,355	7/5/88	Sullivan			
	AC	5,475,317	12/12/95	Smith			
	AD	5,495,667	3/5/96	Farrworth et al.			
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AE	C.M. 09/003,184, Filed 3/27/98; Akum-tech; Amendment filed 12/18/00; CFA filed 7/28/00; Amendment filed 3/2/00; Amendment filed 8/23/02; Original Application filed 3/27/98, Pending Claims.					
VN	AF	Advertisement for Probe Technology; <a href="http://www.idinet.com">www.idinet.com</a> ; Interconnect Devices, Inc.; 1 page; 3/6/98 <b>EL979977639</b>					
VN	AG	Good Things Come in Small BGA/CSP Packages; <a href="http://www.johnstech.com/4/handbook/page9.html">www.johnstech.com/4/handbook/page9.html</a> ; 1 page; 3/5/98					
VN	AH	Product Description for Double Ended Probes, B1052 Series; <a href="http://www.testprobe.com/products/b1052.html">www.testprobe.com/products/b1052.html</a> ; Rika Denshi America, Inc.; 1 page; 2/4/98.					
VN	AI	Product Description for Test Centers, RM-500 Series Probes; <a href="http://www.testprobe.com/products/rm500.html">www.testprobe.com/products/rm500.html</a> ; Rika Denshi America, Inc.; 1 page; 2/4/98.					
VN	AJ	Product Description for Cost Effective Interconnections for High I/O Products; <a href="http://www.testprobe.com/products/fo.htm#b1303">www.testprobe.com/products/fo.htm#b1303</a> ; Rika Denshi America, Inc.; 1 page; 2/4/98.					
VN	AK	Product Description for Ball Grid Probe B1303-C3; <a href="http://www.testprobe.com/products/fo.htm#b1303">www.testprobe.com/products/fo.htm#b1303</a> ; Rika Denshi America, Inc.; 1 page; 2/4/98.					
VN	AL	Product Description for Test Socket Contacts; <a href="http://www.johnstech.com/4/handbook/page9.html">www.johnstech.com/4/handbook/page9.html</a> ; 1 page; 3/5/98					
EXAMINER <i>nmk Nguyen</i>				DATE CONSIDERED 03/22/2002			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO-151		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1684		SERIAL NO. 09527248	
LIST OF ART CITED BY APPLICANT (See several sheets if necessary)				APPLICANT Micron Technology, Inc.		FILING DATE April 4, 2001	
				GROUP 2829			
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA	4,006,909	2/3/1977	Ottendorf et al.			
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
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EXAMINER <i>and Nguyen</i>				DATE CONSIDERED 09/08/04			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1684		SERIAL NO. 09527248	
LIST OF ART CITED BY APPLICANT (Use reverse side if necessary)				APPLICANT Micron Technology, Inc.			
				FILING DATE April 4, 2001		GROUP 2829	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
VN	AA	5,503,034	4/2/1996	Ames et al.			
VN	AB	5,964,395	2/1/2000	Glovatsky et al.			
VN	AC	5,645,764	7/1/97	Angelopoulos et al.			
VN	AD	5,437,189	8/1995	Brown et al.			
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	AF						
	AG						
	AH						
OTHER REFERENCES (including Author, Title, Date, Periodic Pages, Etc.)							
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	AI			EV372455367			
EXAMINER <i>mh Nguyen</i>				DATE CONSIDERED 09/08/04			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1684		SERIAL NO. 09/827,248	
 PART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.			
				FILING DATE April 4, 2001		GROUP 2829	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA	4,006,909	2/8/1977	Ollendorf et al.			
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	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
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	AI						
	AK		EL979954690				
	AL						
EXAMINER <i>anh Nguyen</i>				DATE CONSIDERED 02/17/05			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							